

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.221C1	APPLICATION NO. Unknown <b>10/775,582</b>
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Fulkerson, et al.	
		FILING DATE Herewith	GROUP Unknown <b>2818</b>

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TL	Daughton, James M., "Advanced MRAM Concepts" 2/7/01 <u>NVE Cooperation</u> retrieved from the Internet: <URL: www.nve.com/otherbiz/mram.pdf> retrieved on January 25, 2002
TL	Lee, et al., "Separation of Contributions to Spin Valve Interlayer Exchange Coupling Field by Temperature Dependent Coupling Field Measurements" [online] 48 <sup>th</sup> MMM Conference Seattle, Washington 2001 pp. 1-16 [retrieved on January 25, 2002] Retrieved from the Internet: <URL:www.andrew.cmu.edu/~zlee/mmm.pdf>
TL	"Magnetoelectronics" [online] [retrieved on January 25, 2002] Retrieved from the Internet: <URL: www.ipm.virginia.edu/research/PVD/Pubs/thesis7/chapter2.PDF> Chapter 2 pp. 7-34
TL	"Non-Volatile Memory (MRAM)" <u>ANXXX</u> [online] Honeywell <retrieved on November 19, 2001> <URL: www.ssec.honeywell.com/avionics/h_gmr.pdf> pp. 1-4

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EXAMINER <b>Thoyle</b>	DATE CONSIDERED <b>6/3/04</b>
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	